

MSKSEMI

SEMICONDUCTOR



ESD



TVS



TSS



MOV

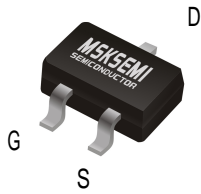


GDT

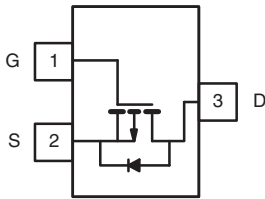


PLED

Product data sheet



SOT-23



Features

- -18V, -2.0A, $R_{DS(ON)} = 60m\Omega @ V_{GS} = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

| | | |
|-------|-------|-------|
| BVDSS | RDSON | ID |
| -18V | 60mΩ | -2.0A |

Absolute Maximum Ratings $T_C=25^\circ C$ unless otherwise noted

| Symbol | Parameter | Rating | Units |
|-----------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | -18 | V |
| V_{GS} | Gate-Source Voltage | ± 12 | V |
| I_D | Drain Current – Continuous ($T_C=25^\circ C$) | -2.0 | A |
| | Drain Current – Continuous ($T_C=100^\circ C$) | -0.95 | A |
| I_{DM} | Drain Current – Pulsed ¹ | -8.0 | A |
| P_D | Power Dissipation ($T_C=25^\circ C$) | 312 | mW |
| | Power Dissipation – Derate above 25°C | 2.5 | mW/°C |
| T_{STG} | Storage Temperature Range | -55 to 150 | °C |
| T_J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Characteristics

| Symbol | Parameter | Typ. | Max. | Unit |
|-----------------|--|------|------|------|
| $R_{\theta JA}$ | Thermal Resistance Junction to ambient | --- | 400 | °C/W |

Electrical Characteristics (T_J=25 °C, unless otherwise noted)
Off Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|----------------------------------|---|---|------|-------|------|------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =-250uA | -18 | --- | --- | V |
| BV _{DSS} T _J | BV _{DSS} Temperature Coefficient | Reference to 25°C, I _D =-1mA | --- | -0.01 | --- | V/°C |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =-18V, V _{GS} =0V, T _J =25 | --- | --- | -1 | uA |
| | | V _{DS} =-16V, V _{GS} =0V, T _J =125 | --- | --- | -10 | uA |
| I _{GSS} | Gate-Source Leakage Current | V _{GS} 12V, V _{DS} =0V | --- | --- | 100 | nA |

On Characteristics

| | | | | | | |
|---------------------|---|---|------|------|------|-------|
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} =-4.5V, I _D =-2A | --- | 60 | 110 | mΩ |
| | | V _{GS} =-2.5V, I _D =-1A | --- | 110 | 135 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =-250uA | -0.3 | -0.6 | -1.0 | V |
| V _{GS(th)} | V _{GS(th)} Temperature Coefficient | | --- | 3 | --- | mV/°C |
| g _{fs} | Forward Transconductance | V _{DS} =-10V, I _S =-1A | --- | 2.2 | --- | S |

Dynamic and switching Characteristics

| | | | | | | |
|---------------------|-------------------------------------|---|-----|------|-----|----|
| Q _g | Total Gate Charge ^{2, 3} | V _{DS} =-10V, V _{GS} =-4.5V, I _D =-1A | --- | 4.8 | 8 | nC |
| Q _{gs} | Gate-Source Charge ^{2, 3} | | --- | 0.5 | 1 | |
| Q _{gd} | Gate-Drain Charge ^{2, 3} | | --- | 1.9 | 4 | |
| T _{d(on)} | Turn-On Delay Time ^{2, 3} | V _{DD} =-10V, V _{GS} =-4.5V, R _G =25Ω I _D =-1A | --- | 3.5 | 7 | ns |
| T _r | Rise Time ^{2, 3} | | --- | 12.6 | 24 | |
| T _{d(off)} | Turn-Off Delay Time ^{2, 3} | | --- | 32.6 | 62 | |
| T _f | Fall Time ^{2, 3} | | --- | 8.4 | 16 | |
| C _{iss} | Input Capacitance | V _{DS} =-15V, V _{GS} =0V, F=1MHz | --- | 350 | 510 | pF |
| C _{oss} | Output Capacitance | | --- | 65 | 95 | |
| C _{rss} | Reverse Transfer Capacitance | | --- | 50 | 75 | |

Drain-Source Diode Characteristics and Maximum Ratings

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-----------------|---------------------------|--|------|------|------|------|
| I _S | Continuous Source Current | V _G =V _D =0V, Force Current | --- | --- | -2.0 | A |
| I _{SM} | Pulsed Source Current | | --- | --- | -4.0 | A |
| V _{SD} | Diode Forward Voltage | V _{GS} =0V, I _S =-1A, T _J =25°C | --- | --- | -1.2 | V |

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed, pulse width ≤300us, duty cycle ≤2%.
3. Essentially independent of operating temperature.

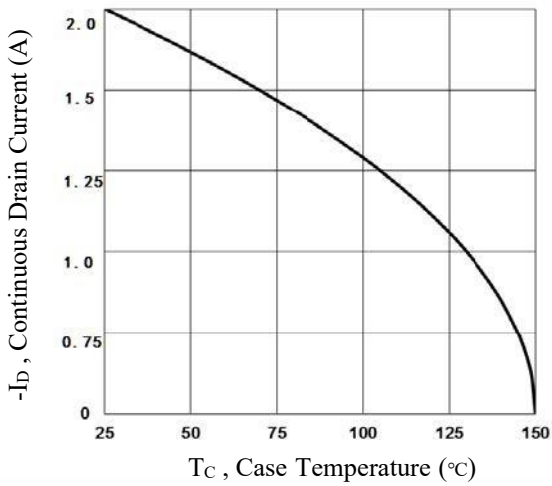


Fig.1 Continuous Drain Current vs. T_C

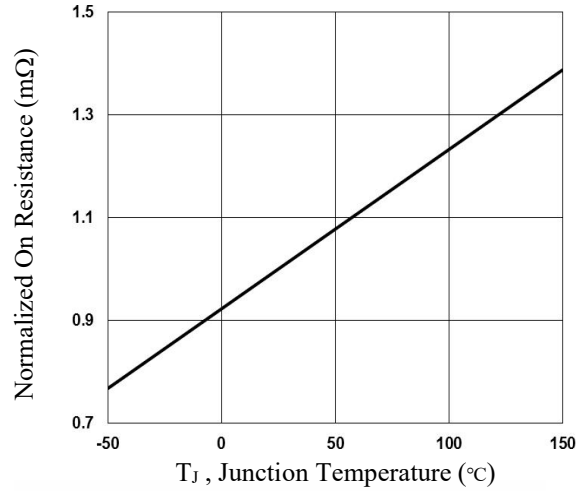


Fig.2 Normalized $R_{DS(on)}$ vs. T_J

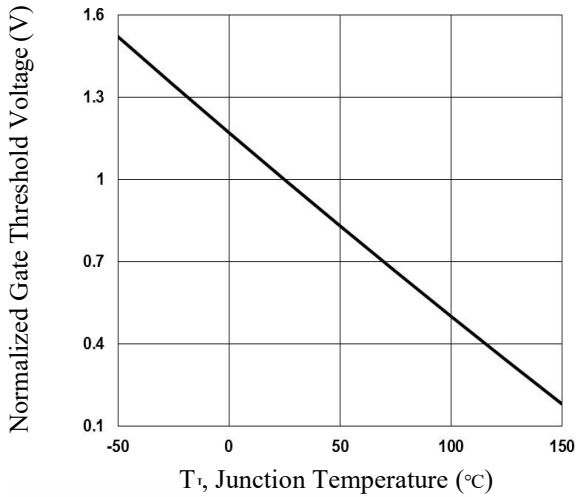


Fig.3 Normalized V_{th} vs. T_J

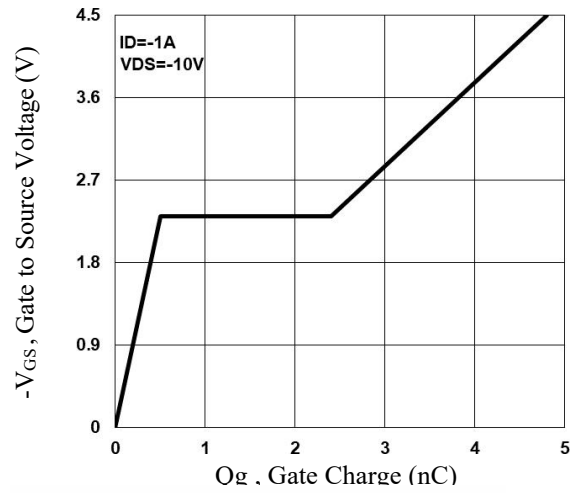


Fig.4 Gate Charge Waveform

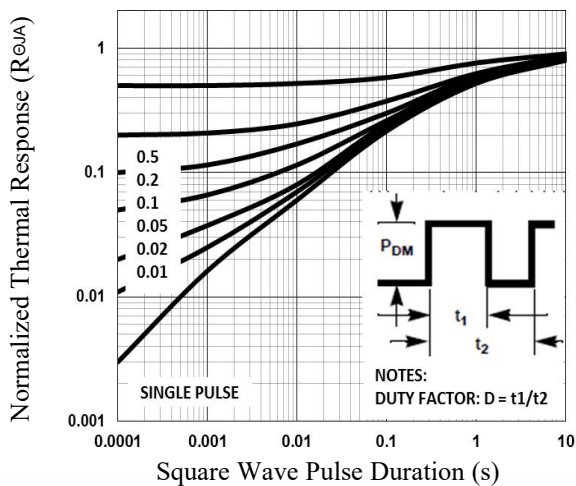


Fig.5 Normalized Transient Response

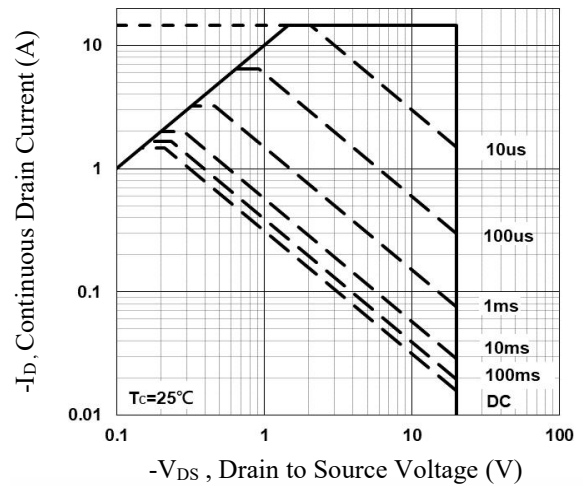


Fig.6 Maximum Safe Operation Area

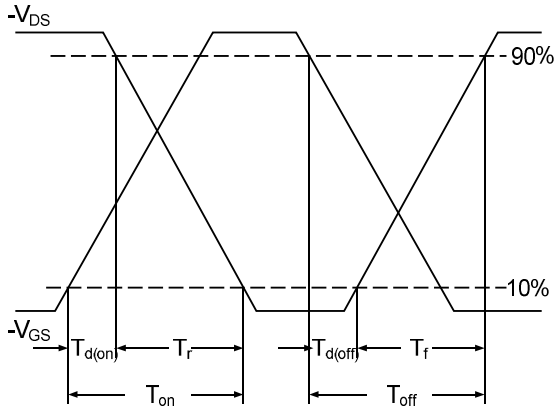


Fig.7 Switching Time Waveform

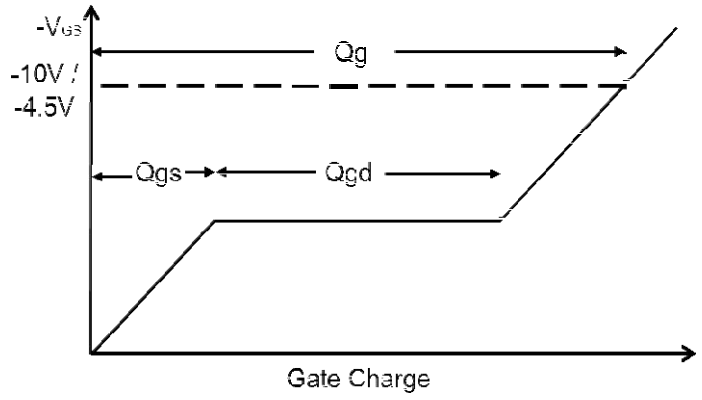
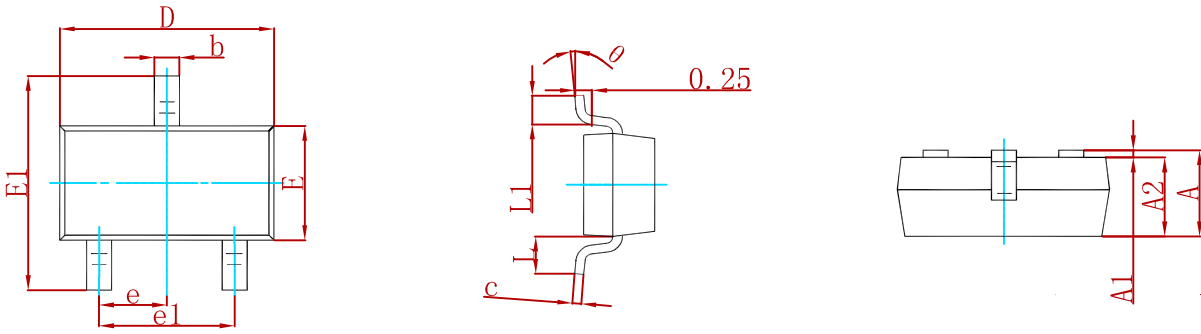


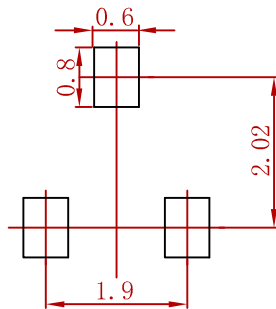
Fig.8 Gate Charge Waveform

PACKAGE MECHANICAL DATA



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| A | 0.900 | 1.150 | 0.035 | 0.045 |
| A1 | 0.000 | 0.100 | 0.000 | 0.004 |
| A2 | 0.900 | 1.050 | 0.035 | 0.041 |
| b | 0.300 | 0.500 | 0.012 | 0.020 |
| c | 0.080 | 0.150 | 0.003 | 0.006 |
| D | 2.800 | 3.000 | 0.110 | 0.118 |
| E | 1.200 | 1.400 | 0.047 | 0.055 |
| E1 | 2.250 | 2.550 | 0.089 | 0.100 |
| e | 0.950 TYP | | 0.037 TYP | |
| e1 | 1.800 | 2.000 | 0.071 | 0.079 |
| L | 0.550 REF | | 0.022 REF | |
| L1 | 0.300 | 0.500 | 0.012 | 0.020 |
| θ | 0° | 8° | 0° | 8° |

Suggested Pad Layout



- Note:
1. Controlling dimension: in millimeters.
 2. General tolerance: ± 0.05mm.
 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

| P/N | PKG | QTY |
|----------------|--------|------|
| NTR2101PT1G-MS | SOT-23 | 3000 |

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